ON Semiconductor

INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION
Generic Copy

13 May 2008

SUBJECT: ON Semiconductor Initial Product/Process Change Notification #16114

TITLE: Additional Fab Capacity for SO8FL Package

PROPOSED FIRST SHIP DATE: 13 Sep 2008

AFFECTED CHANGE CATEGORY: ON Semiconductor Wafer Fab Site

AFFECTED PRODUCT DIVISION: PowerFET Business Unit

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor Sales Office or Larry DeLuca<larry.deluca@onsemi.com >

NOTIFICATION TYPE:

Initial Product/Process Change Notification (IPCN)

First change notification sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan.

The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN).

This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change.

DESCRIPTION AND PURPOSE:

This Initial PCN #16114 is to announce that ON Semiconductor will be adding wafer fabrication capacity on their N-channel Trench MOSFET technology for their SO8FL product types. The facility is located in Gresham, Oregon which is fully certified and qualified for this Silicon platform with other packages. Device quality and reliability will continue to meet ON Semiconductors high standards. Product may begin to ship using Die fabricated in the Gresham factory at the expiration of the Final PCN.

Initial Product/Process Change Notification #16114

QUALIFICATION PLAN:

Test: High Temperature Reverse Bias (HTRB)
Conditions: Vds= 80% Vds rating, Ta=150'C, 504-Hrs

Test: High Temperature Gate Bias (HTGB)
Conditions: Vgs= 100%Vgs, Ta=150'C, 504-Hrs.

Test: High Temperature Storage Life (HTSL)
Conditions: Ta=150'C, 504-Hrs.

Test: Intermittent Operating Life (IOL-PC)
Conditions: Ta=+25'C, delta Tj=100'C, 2-min on/off, 7.5K-cycles

Test: Temperature Cycling (TC-PC)
Conditions: Ta=-65'C/+150'C, Air-to-Air, Dwell >=10-min, 500-cy

Test: Highly Accelerated Stress Test (HAST-PC)
Conditions: Ta=121'C, RH=100%, P=15psig, 96-Hrs

Test: Autoclave Test (AC-PC)
Conditions: Ta=121'C, P=15psi, RH=100%, 96-Hrs

Test: Electrical Distribution Data

Initial Product/Process Change Notification #16114

AFFECTED DEVICE LIST:

PART

NTMFS4821NT1G
NTMFS4821NT3G
NTMFS4823NT1G
NTMFS4823NT3G
NTMFS4833NT1G
NTMFS4833NT3G
NTMFS4834NT1G
NTMFS4834NT3G
NTMFS4835NT1G
NTMFS4835NT3G
NTMFS4836NT1G
NTMFS4836NT3G
NTMFS4837NHT1G
NTMFS4837NHT3G
NTMFS4837NT1G
NTMFS4837NT3G
NTMFS4839NHT1G
NTMFS4839NHT3G
NTMFS4839NT1G
NTMFS4839NT3G
NTMFS4841NHT1G
NTMFS4841NHT3G
NTMFS4841NT1G
NTMFS4841NT3G
NTMFS4845NT1G
NTMFS4845NT3G
NTMFS4846NT1G
NTMFS4846NT3G
NTMFS4847NT1G
NTMFS4847NT3G
NTMFS4849NT1G
NTMFS4849NT3G
NTMFS4851NT1G
NTMFS4851NT3G